

# IMPERFECTIONS IN SOLIDS

# Single crystals

- **Periodic and repeated arrangement of atoms is perfect or extends throughout the entirety of the specimen**
- **Translation: integer multiple of lattice constants  $\rightarrow$  identical position in another unit cell**
- **Can be produced naturally and artificially( eg. Si: Czochralski)**



# Types of Imperfections

- Vacancy atoms
- Interstitial atoms
- Substitutional atoms

Point defects

- Dislocations

Line defects

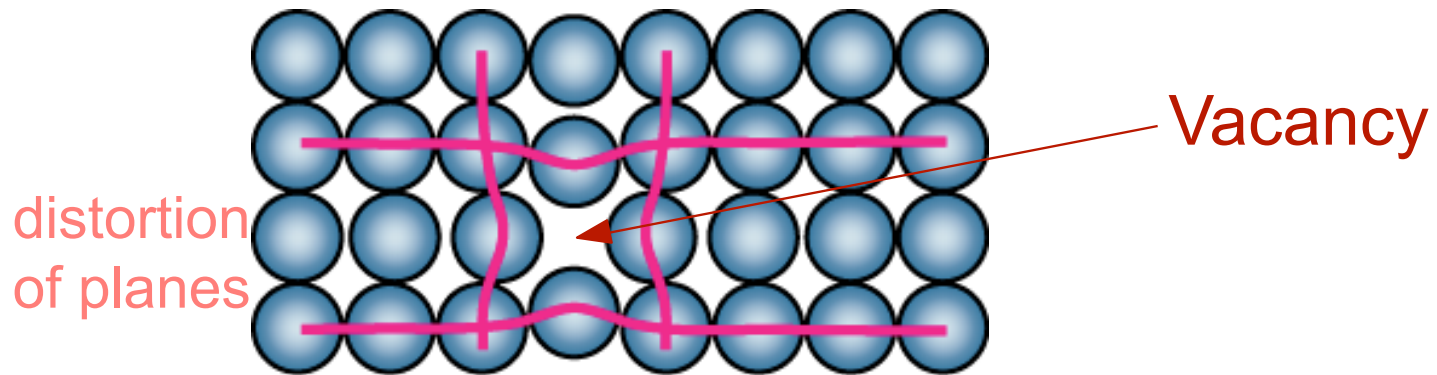
- Grain Boundaries

Area defects

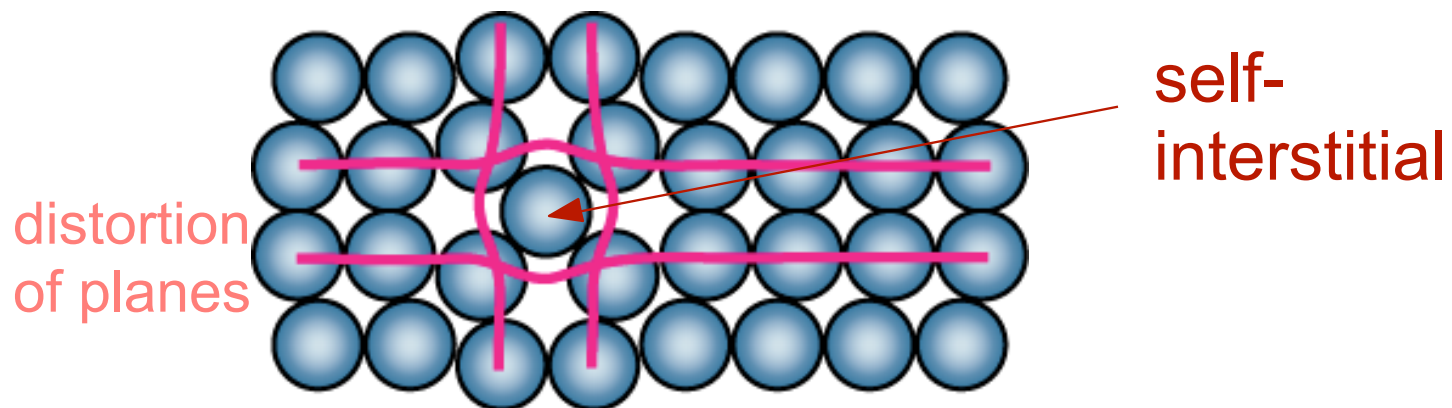


# Point Defects

- **Vacancies:**  
-vacant atomic sites in a structure.



- **Self-Interstitials:**  
-"extra" atoms positioned between atomic sites.



# Equilibrium Concentration: Point Defects

- Equilibrium concentration varies with temperature!

No. of defects  $\rightarrow N_v$

No. of potential defect sites.  $\rightarrow N$

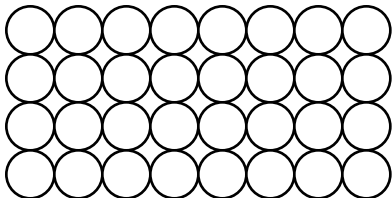
$$\frac{N_v}{N} = \exp \left( \frac{-Q_v}{kT} \right)$$

Activation energy  $\rightarrow Q_v$

Boltzmann's constant  $\rightarrow k$

Temperature  $\rightarrow T$

(1.38 x 10<sup>-23</sup> J/atom-K)  
(8.62 x 10<sup>-5</sup> eV/atom-K)

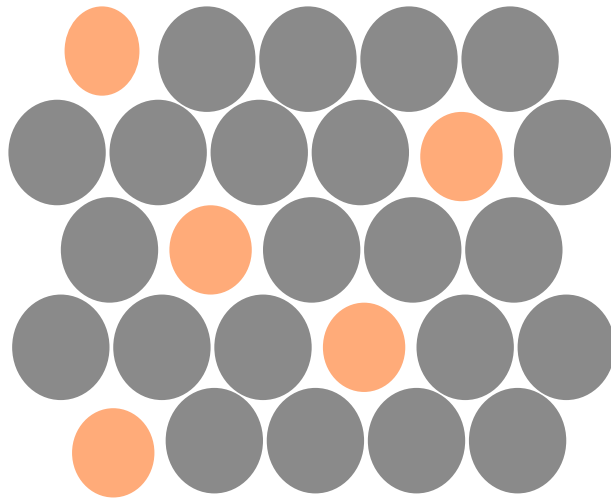


Each lattice site is a potential vacancy site

# Point Defects in Alloys

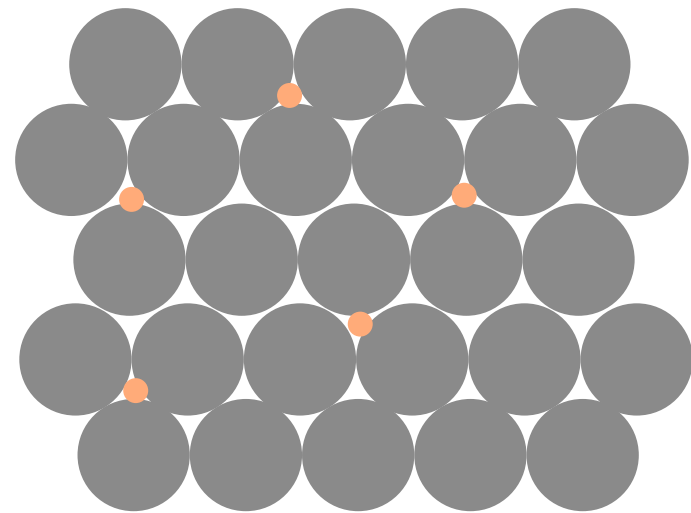
Two outcomes if impurity (B) added to host (A):

- **Solid solution** of **B** in A (i.e., random dist. of point defects)



**Substitutional** solid soln.  
(e.g., **Cu** in Ni)

OR



**Interstitial** solid soln.  
(e.g., **C** in Fe)

# Imperfections in Solids

Conditions for substitutional solid solution (S.S.)

- W. Hume – Rothery rule
  - 1.  $\Delta r$  (atomic radius) < 15%
  - 2. Proximity in periodic table
    - i.e., similar electronegativities
  - 3. Same crystal structure for pure metals
  - 4. Valency
    - All else being equal, a metal will have a greater tendency to dissolve a metal of higher valency than one of lower valency



# Imperfections in Solids

- Specification of composition

– weight percent  $C_1 = \frac{m_1}{m_1 + m_2} \times 100$

$m_1$  = mass of component 1

– atom percent  $C'_1 = \frac{n_{m1}}{n_{m1} + n_{m2}} \times 100$

$n_{m1}$  = number of moles of component 1





# Linear Defects

## Linear Defects (Dislocations)

- Are one-dimensional defects around which atoms are misaligned

Burgers vector,  $\mathbf{b}$ : measure of lattice distortion

# Imperfections in Solids

## Edge Dislocation

- extra half-plane of atoms inserted in a crystal structure
- $\mathbf{b} \perp$  to dislocation line

Edge  
dislocation  
line

Burgers vector

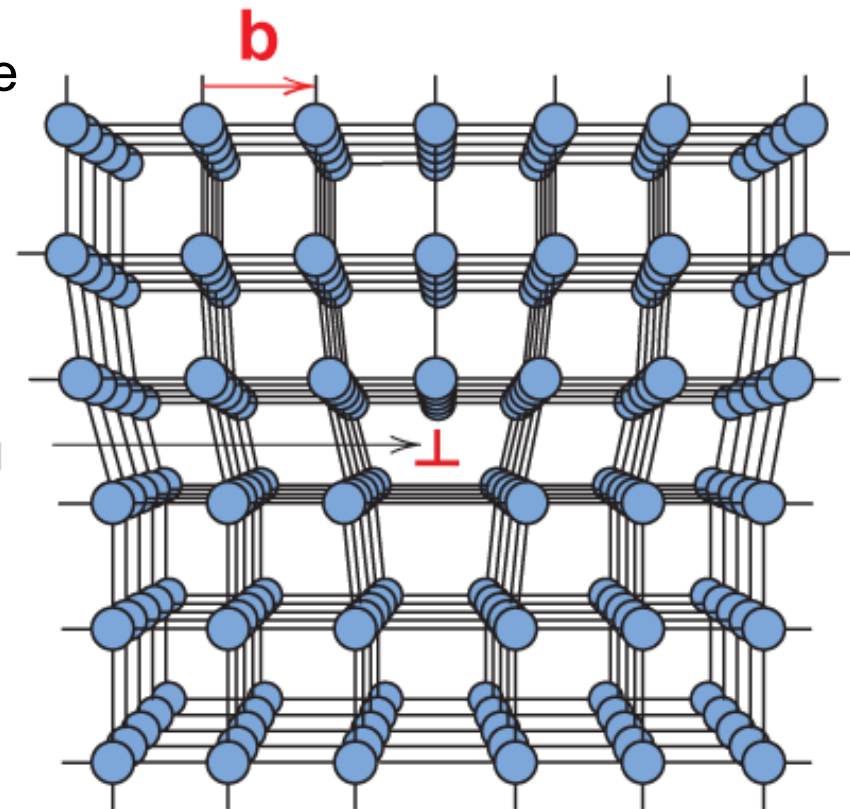


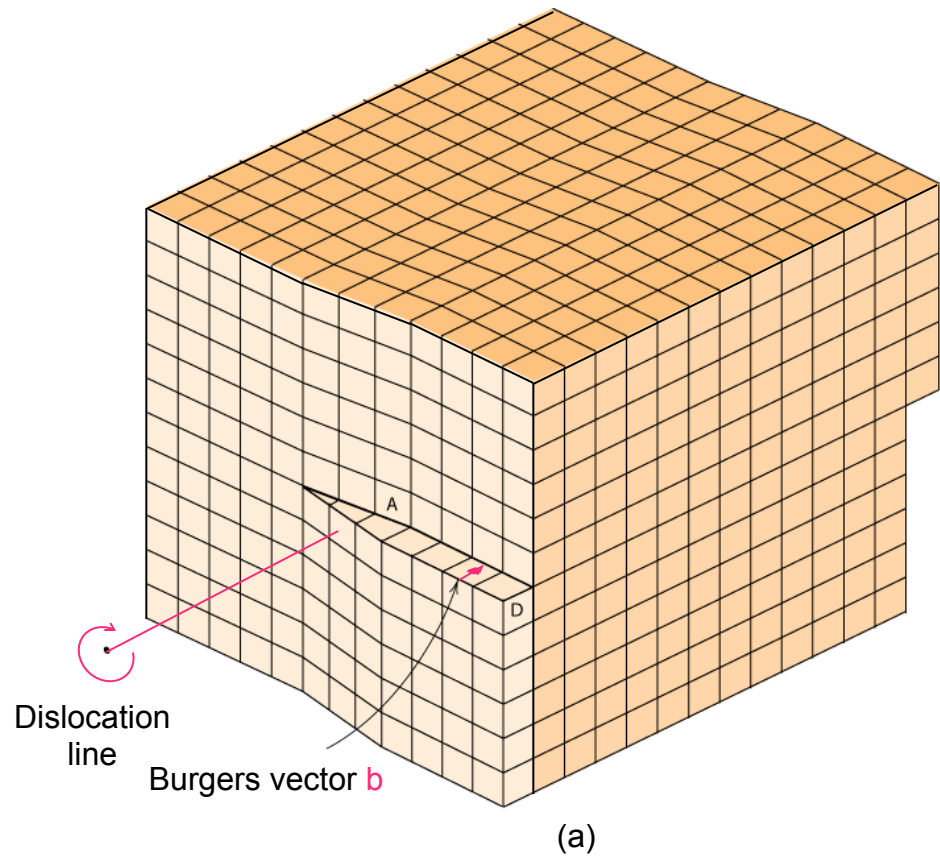
Fig. 4.3, Callister 7e.

# Imperfections in Solids

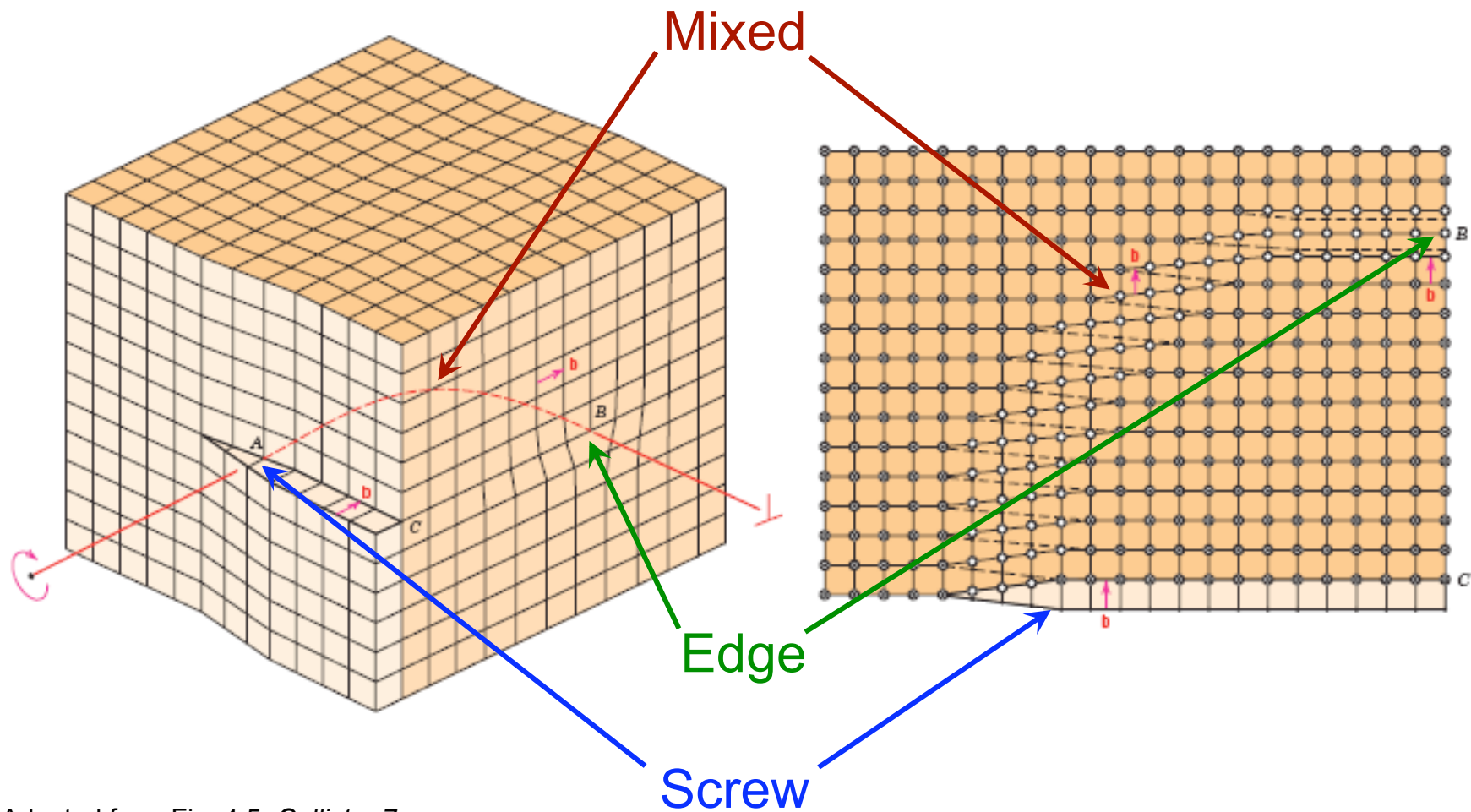
## Screw Dislocation

spiral planar ramp resulting from shear deformation

$\mathbf{b} \parallel$  to dislocation line



# Edge, Screw, and Mixed Dislocations

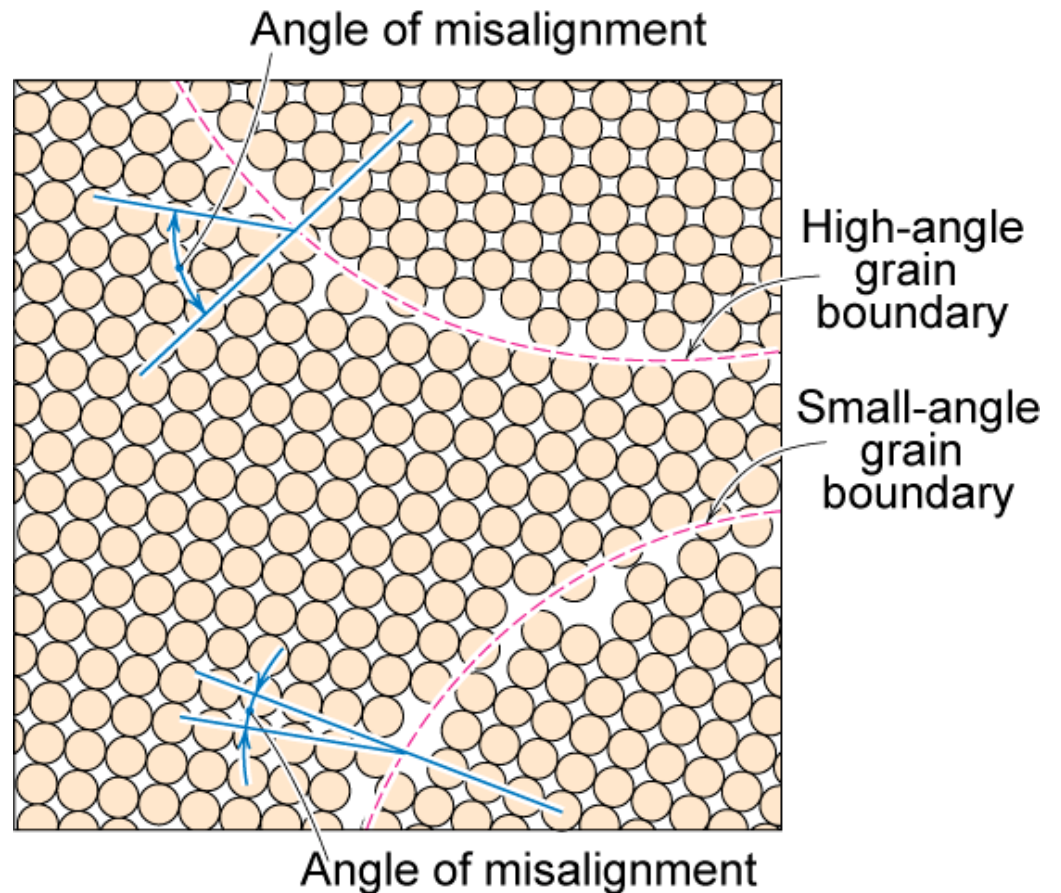


Adapted from Fig. 4.5, Callister 7e.

# Grain Boundaries and Polycrystalline Materials

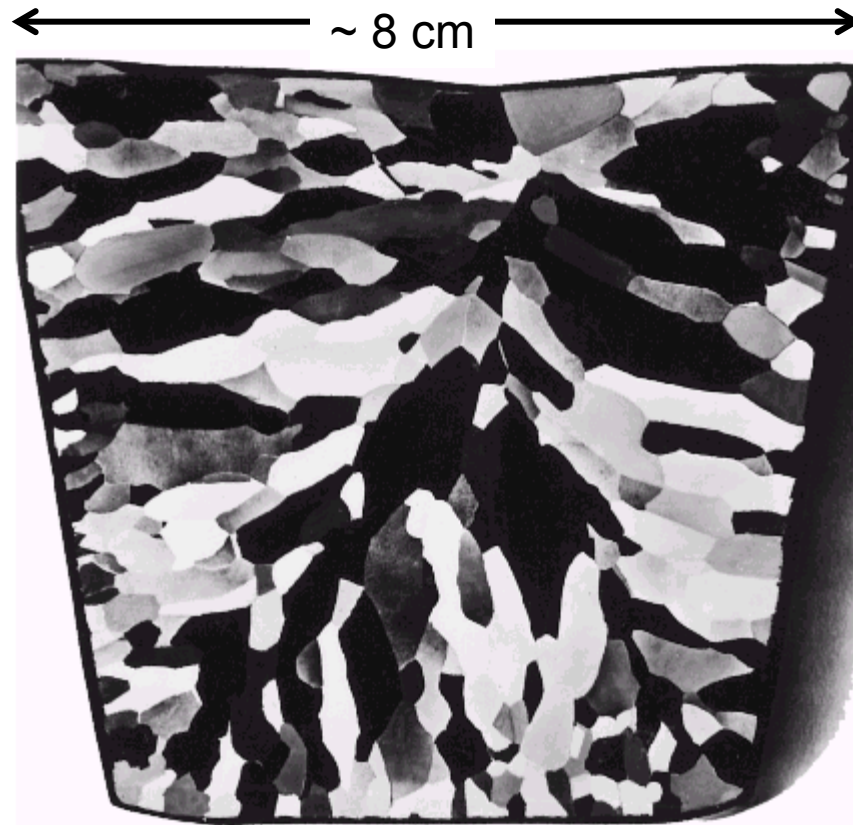
## Grain Boundaries

- regions between crystals
- transition from lattice of one region to that of the other
- slightly disordered
- low density in grain boundaries
  - high mobility
  - high diffusivity
  - high chemical reactivity



Adapted from Fig. 4.7, *Callister 7e*.

# Polycrystalline Materials



Optical Micrograph of Polycrystalline lead ingot

# Microscopic Examination

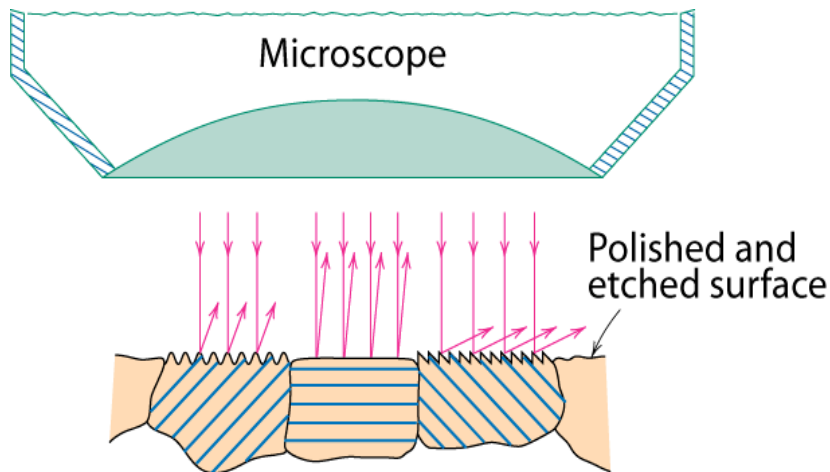
- Crystallites (grains) and grain boundaries.  
Vary considerably in size. Can be quite large
  - ex: Large single crystal of quartz or diamond or Si
  - ex: Aluminum light post or garbage can - see the individual grains
- Crystallites (grains) can be quite small (mm or less) – necessary to observe with a microscope.





# Optical Microscopy

- Can resolve features as small as  $\sim \lambda/2$  (eg.  $\sim 250$  nm).
- Polishing removes surface features (e.g., scratches)
- Etching changes reflectance, depending on crystal orientation.



Micrograph of  
brass (a Cu-Zn alloy)





# Microscopy

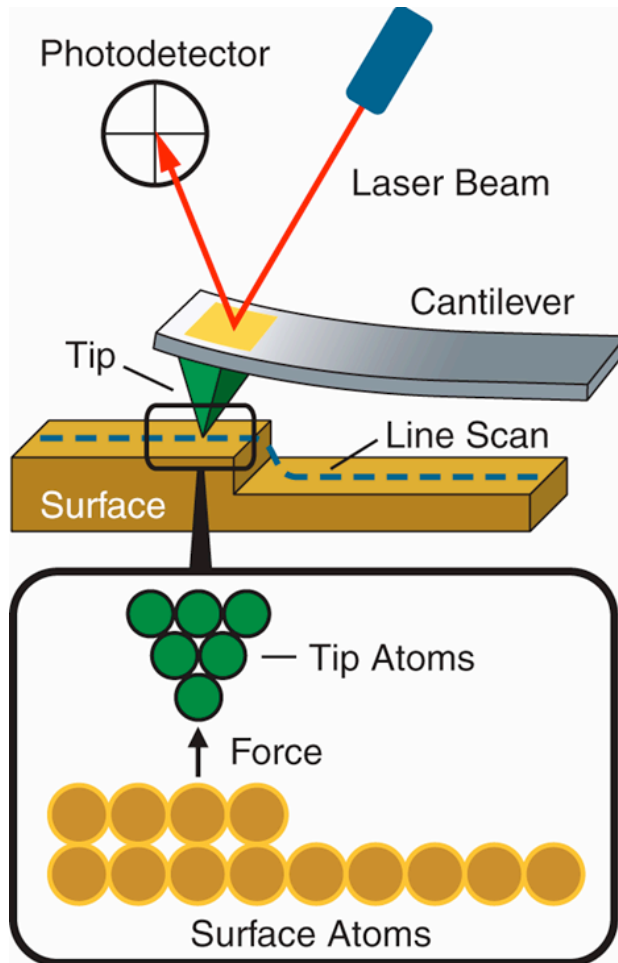
Optical resolution ca.  $\sim 10^{-7}$  m  $\sim$  250 nm

For higher resolution need shorter wavelength

- X-Rays? Difficult to focus (Synchrotron).
- Electrons (SEM, TEM)
  - wavelengths ca. 3 pm (0.003 nm)
    - (Magnification - 1,000,000X)
  - Atomic resolution possible
  - Electron beam focused by magnetic lenses.

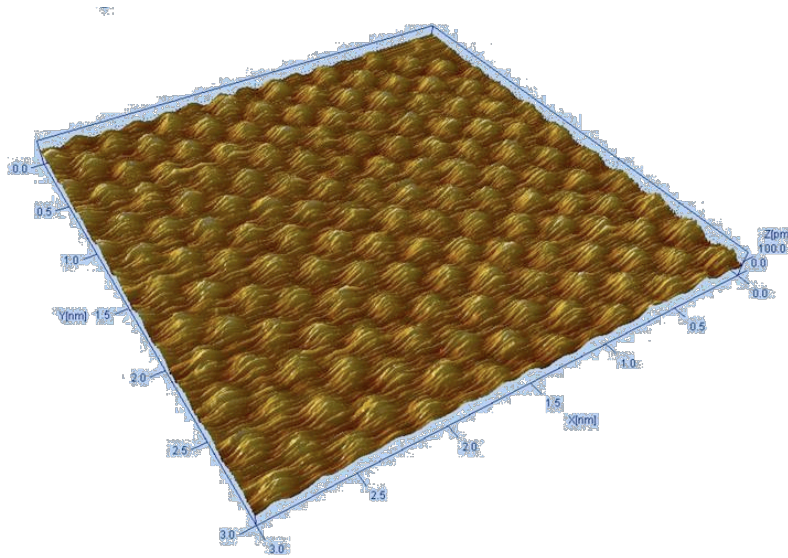
# Atomic Force Microscope

(a type of Scanning Probe Microscope)

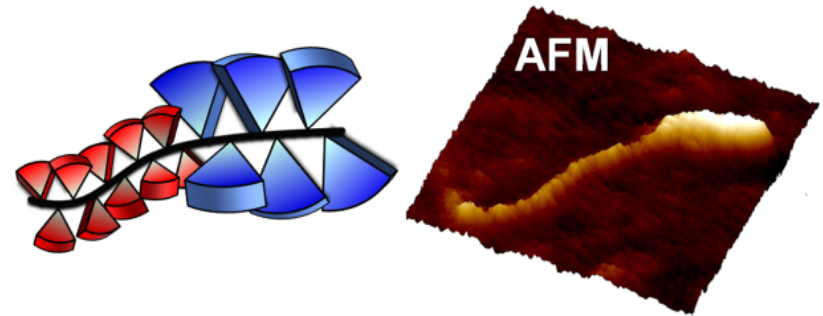


# Atomic Force Microscope

(a type of Scanning Probe Microscope)



Graphite atoms



Diblock copolymer

# Relevant Courses in MSE

MSE 331 Crystallography and Structure (3) Fall

MSE 333 Materials Characterization (3) Spring-  
**Rolandi**

MSE 484 Materials Chemistry (3)- NW Raschke

MSE 510 Bonding, Crystallography, and Symmetry-  
Related Properties of Materials (3)

MSE 512 Experimental Transmission Electron  
Microscopy (3)

MSE 541 Defects in Materials (3)

